

Semiconductor Monitoring Burn-in Test Chamber ▶▶

ETSP-BTC series

ETSP-BTC series are Semiconductor Monitoring Burn-In Test chambers to stress semiconductor packaged devices to ensure optimum performance as well as to weed out defective semiconductor packaged devices which can cause reliability problems in the end product.

ETSP-BTC series are manufactured according to the Total Quality procedures, in compliance with the ISO 9001 standard.



ETSP-BTC series

General Features

- Uniform high accurate and reliable temperature control
- Easy of operation and simplicity
- Friendly, flexible, up-to date control and management systems.
- Allows easy servicing and upgrades.
- Selectable between manual door type (BTC 1000) and automatic door type (BTC 2000).
- Computer control is available.
- Network connection of several chambers to a single "master" control unit allowing centralized supervision both in local and remote mode.

Technical Features

Temperature range		40 °C ~ 150 °C (changeable according to user's demand)
Temperature uniformity		less than ± 0.5 °C
Temperature rising time		RT to 125 °C less than 50 minutes
Temperature cooling time		125 °C to RT less than 50 minutes
Input Power Requirements		230V $\pm 10\%$, 380V $\pm 10\%$, 50Hz/60Hz, 1PH/3PH